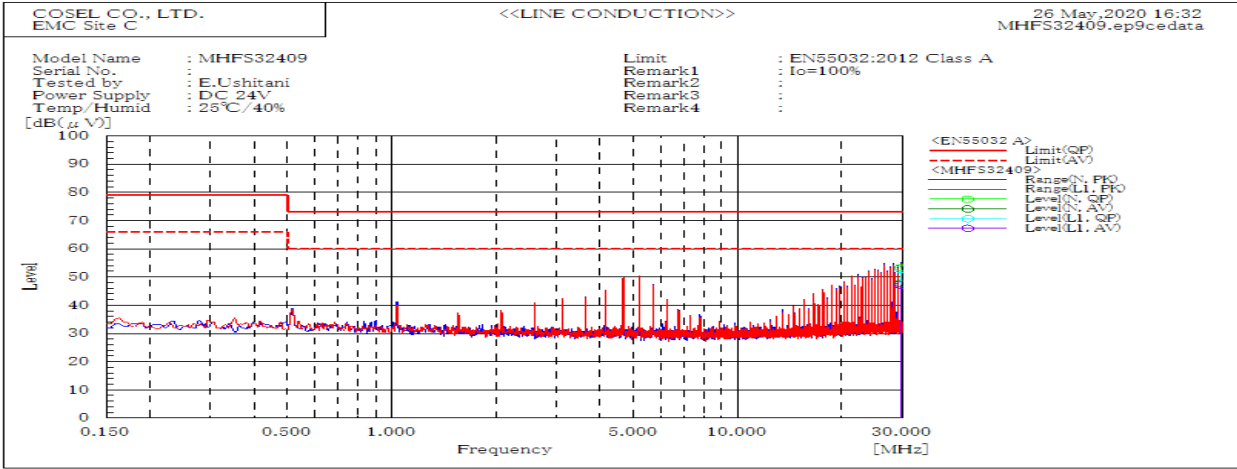
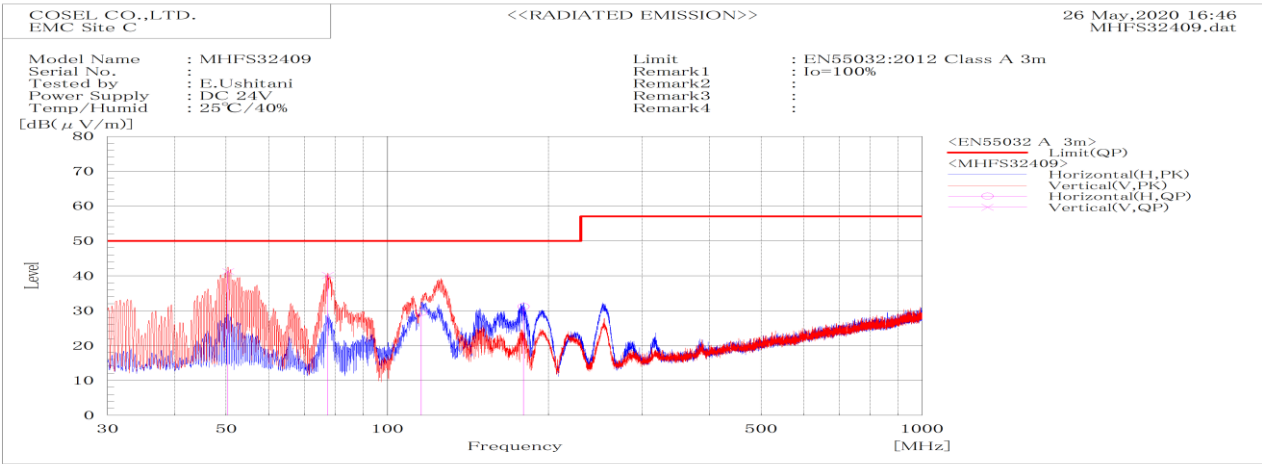


DATA SHEET		Date	04-Jun-20
Model	MHFS32409	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



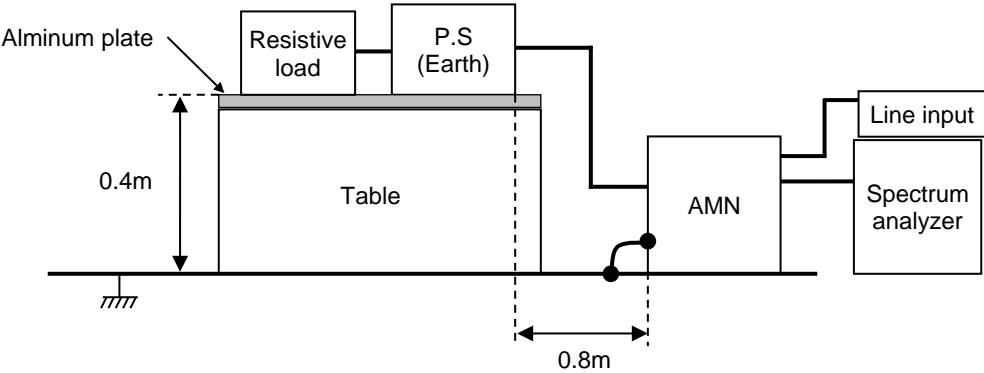
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
29.585	L1	52.7	47.1	73	60	20.3	12.9	Pass	
29.583	N	53.4	47.8	73	60	19.6	12.2	Pass	



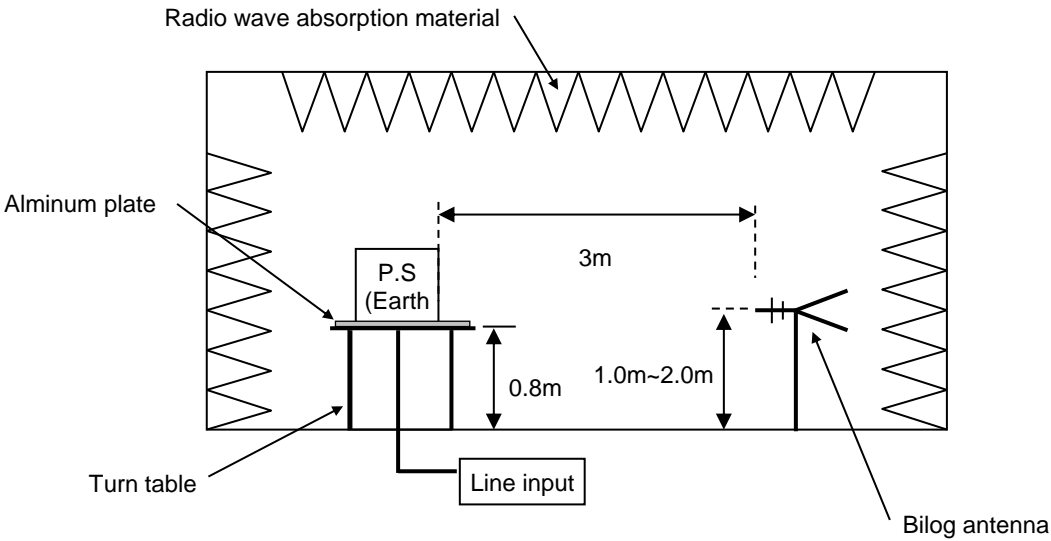
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
115.87	H	Stable	29.5	50	20.5	Pass	182.4	0	
179.835	H	Stable	31.2	50	18.8	Pass	200	4.1	
50.403	V	Stable	41.2	50	8.8	Pass	100	0	
77.417	V	Stable	40.1	50	9.9	Pass	103.4	22.3	

DATA SHEET		Date	04-Jun-20
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission



# Conditions

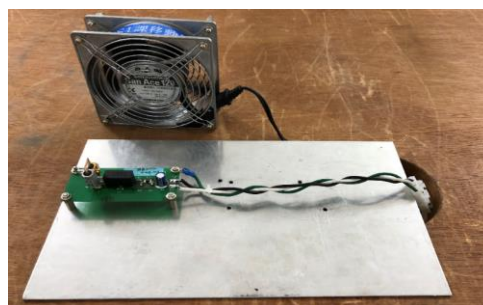
Test : EMI  
Model Name: MHFS3□□

○Photographs of Test Set-Up

## LINE CONDUCTION



## RADIATED EMISSION



○Testing circuitry

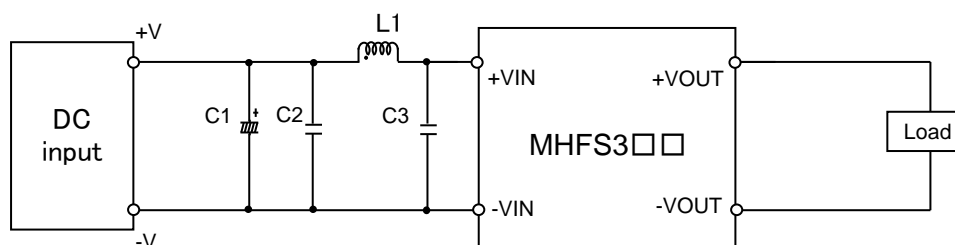


Fig.1 Testing circuitry

C1 :	MHFS312□□	50V 100μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS324□□	-
	MHFS348□□	-
C2 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS312□□	1200mA 4.7μ H Inductor(LQH32PN4R7NNCL MURATA MANUFACTURING)
	MHFS324□□	900mA 10μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
	MHFS348□□	550mA 22μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)